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# Research on dielectric and piezoelectric properties of Ta-doped 0.68Pb(Mg<sub>1/3</sub>Nb<sub>2/3</sub>)O<sub>3</sub>–0.32PbTiO<sub>3</sub> ceramics

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#### **Abstract**

Pure perovskite 0.68Pb [Mg<sub>1/3</sub>(Nb<sub>(1-x)</sub>Ta<sub>x</sub>)<sub>2/3</sub>]O<sub>3</sub>-0.32PbTiO<sub>3</sub> (0.68PMNTa-0.32PT) ceramics were prepared by one-step calcination method using Mg(NO<sub>3</sub>)<sub>2</sub> instead of MgO as starting chemical. The dielectric properties as a function of temperature and P-E and  $\varepsilon$ -E loops were investigated in this work. The  $T_{\rm m}$  and  $T_{\rm c}$  shift down for  $\sim$ 13 °C with Ta addition. The  $\varepsilon_{\rm m}$  with Ta-doping is higher than that without doping. Both of the diffusion phase transition and frequency dispersion are weak, but the relaxor feature with Ta-doping is more apparent than that without doping. Both of the values of  $P_{\rm r}$  and  $E_{\rm c}$  decrease with Ta addition, and the values of remnant and maximum strain increase with Ta-doping. © 2004 Elsevier Ltd and Techna Group S.r.l. All rights reserved.

Keywords: C. Dielectric properties; C. Piezoelectric properties; PMN-PT; Ta-doped; One-step calcination method

#### 1. Introduction

Lead magnesium niobate-lead titanate (PMN-PT) is a solid solution of relaxor ferroelectric Pb(Mg<sub>1/3</sub>Nb<sub>2/3</sub>)O<sub>3</sub> (PMN) and normal ferroelectric PbTiO<sub>3</sub> (PT) [1]. PMN-PT materials with composition near the morphotropic phase boundary (MPB) exhibit unusual high dielectric permittivity, low dielectric loss and high strain, it is a very promising material for the applications of multilayer ceramic capacitors as well as ceramic electrostrictive actuators and electro-mechanical transducers [1-3]. So far, the PMN-PT system has been extensively investigated. Most of the results, however, have concentrated on the processing parameters, microstructure, dielectric, and electrostrictive properties, especially the compositions at 0.90PMN-0.10PT and near the morphotropic phase boundary (MPB). Many alternative techniques to synthesis pyrochlore-free PMN-PT have been developed, such as the two-stage columbite [3], sol-gel [4], and high-energy ball milling [5]. These approaches, however, require either two-step calcination or expensive processes. Therefore, efforts were made to develop a simple, economic and reproducible fabrication technique. A modified oxide method using highly reactive starting materials

would be a good choice. Since  $Mg(NO_3)_2$  is soluble in water as well as in alcohol. It is a better precursor of MgO than MgCO<sub>3</sub>. The PMN ceramic with a perovskite phase has been prepared by one-step calcination method using Mg(NO<sub>3</sub>)<sub>2</sub> instead of MgO [6]. For the tantalum (Ta) is analogous of niobium (Nb), the tantalum impurity is difficult to separate from niobium oxide (Nb<sub>2</sub>O<sub>5</sub>), which is one of the components for preparing PMN–PT ceramics. The dielectric properties of  $(1-y)Pb[Mg_{1/3}(Nb_{(1-x)}Ta_x)_{2/3}]O_3-yPbTiO_3$  (y=0.1, 0.30, 0.35; x=0, 0.1) ceramics prepared by the columbite precursor method have been studied by Wang and Tang [7].

In the present study,  $0.68Pb(Mg_{1/3}Nb_{2/3})O_3-0.32PbTiO_3$  (0.68PMN-0.32PT) was selected as the starting composition, and Nb substituted by Ta with 0 and  $10\,\text{mol.}\%$ . The 0.68PMNTa-0.32PT ceramics were prepared by the onestep calcination method using  $Mg(NO_3)_2$  instead of MgO as starting chemical. The phase composition and dielectric/piezoelectric properties of 0.68PMNTa-0.32PT ceramics were studied.

### 2. Experimental

The compositions of the specimens were calculated according to the general formula  $0.68Pb[Mg_{1/3}(Nb_{(1-x)}Ta_x)_{2/3}]$ 

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 $O_3$ -0.32PbTi $O_3$ , with x = 0, 0.1. Starting chemicals were PbO (purity >99.9%), Nb<sub>2</sub>O<sub>5</sub> (>99.9%), Ta<sub>2</sub>O<sub>5</sub>(>99.9%),  $TiO_2(>99.0\%)$ , and  $Mg(NO_3)\cdot 6H_2O(>98.0\%)$ . The one-step calcination method [6] was used to prepare 0.68PMNTa-0.32PT ceramics. Starting materials in stoichiometric ratio (without any addition of excess amount) were placed with alcohol in a polypropylene bottle and milled with zirconia balls for 5 h, dried in an infrared chamber and calcined at 850 °C for 2 h, then the perovskite precursors were prepared. The precursor powders added with 1 wt.% of polyvinyl alcohol (PVA) were dry ground using an agate mortar, passed through 60-mesh sieves and pressed into disks (12 mm in diameter and 1-2 mm thick) by die pressing at 100 MPa. The binder was burnt-out by heating up to 600 °C for 2 h, then the disks were supported on Al<sub>2</sub>O<sub>3</sub> setters and sintered at 1230 °C for 2 h in a multiple-enclosure crucible setup sealed with perovskite powders of identical composition to minimize the PbO volatilization. The precursor powders and ceramics were analyzed using X-ray diffraction (XRD). The relative amount of perovskite and pyrochlore phase was determined using the formula [6]:

perovskite (%) = 
$$\frac{I_{\text{perov}(1\,1\,0)}}{I_{\text{pyrov}(2\,2\,2)} + I_{\text{perov}(1\,1\,0)}} \times 100$$
 (1)

Both sides of the specimens were polished and electroded, then fired in air at  $550\,^{\circ}\mathrm{C}$  for 30 min to form silver electrode for electrical measurements. A HP4284A impedance analyzer was used to measure the dielectric constants as a function of temperature on heating at frequencies of 1 Hz to  $100\,\mathrm{kHz}$ . The samples were poled by applying a dc field of 3 kV/mm at  $60\,^{\circ}\mathrm{C}$  for  $20\,\mathrm{min}$ .  $d_{33}$  was measured using a  $d_{33}$ -meter. The P-E and  $\varepsilon$ -E was measured using a modified Swayer–Tower circuit and DGS-6 displacement sensor at the frequency of  $0.1\,\mathrm{Hz}$ . The  $0.1\,\mathrm{Hz}$  sine wave voltage was supplied using a Trek 610 high voltage dc amplifier. Strain measurements were performed under mechanically "free" conditions.

#### 3. Results and discussions

## 3.1. XRD analysis

The XRD profiles of the precursors and ceramics of 0.68PMNTa–0.32PT are presented in Fig. 1. In the precursors, which were calcined at 850 °C for 2 h, except perovskite phase small trace of cubic pyrochlore was detected. The relative amount of perovskite and pyrochlore phase was calculated by Eq. (1). It showed 86 and 89% perovskite phase for the powder with 0 and 10 mol.% Ta-doping, respectively. The Ta-doping has little effect on the formation of perovskite. In the ceramics, however, pure perovskite phase was identified. Effectiveness of the one-step calcination method with Mg(NO<sub>3</sub>)<sub>2</sub> instead of MgO in suppression of the pyrochlore formation during perovskite development has thus been proven again in the present study. Meanwhile,

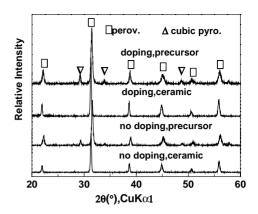


Fig. 1. The XRD patterns of 0.68PMNTa-0.32PT.

the reflection angles decrease after sintering, this may be attributed to grain growth after sintering at 1230 °C. The reflection angles of the Ta-doped sample are smaller than that of the pure sample. This is undoubtedly due to the incorporation of Ta (10 mol.%) during the solid solution formation.

## 3.2. Dielectric properties

Fig. 2 shows the dielectric properties as a function of temperature at 1 kHz for 0.68PMNTa–0.32PT. The dielectric constant ( $\varepsilon$ ) for Ta-doped 0.68PMN–0.32PT ceramic has a sharp peak near  $T_{\rm m}=155.3\,^{\circ}{\rm C}$  for FE–PE phase transition at 1 kHz, corresponding to the curves of  $\tan\delta$  versus  $T_{\rm c}$ , where sharp peaks exist at  $T_{\rm c}=151.5\,^{\circ}{\rm C}$ , while these values of pure 0.68PMN–0.32PT ceramic are  $T_{\rm m}=142.2\,^{\circ}{\rm C}$  and  $T_{\rm c}=138.6\,^{\circ}{\rm C}$ , respectively. The  $T_{\rm m}$  and  $T_{\rm c}$  shift down for about 13  $^{\circ}{\rm C}$  with Ta addition. The value of  $\varepsilon_{\rm m}$  with Tadoping ( $\varepsilon_{\rm m}\sim25,000$ ) is higher than that without doping ( $\varepsilon_{\rm m}\sim24,000$ ).

The temperature dependence of  $\varepsilon$  and  $\tan \delta$  at different frequencies for 0.68PMNTa–0.32PT are presented in Fig. 3.  $\Delta T = T_{\rm m/100\,kHz} - T_{\rm m/1\,kHz}$ , where  $\Delta T$  can be used to figure frequency dispersion. The value of  $\Delta T$  without Ta-doping is 0.6 °C, and that with Ta-doping is 2.1 °C. The sample with Ta addition, thus, has more apparent frequency dispersion than

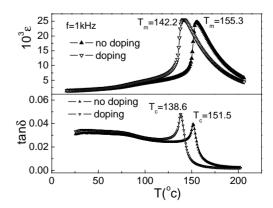
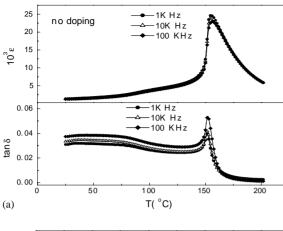


Fig. 2. Temperature dependence of  $\varepsilon$  and  $\tan\delta$  at 1 kHz for 0.68PMNTa=0.32PT ceramic.



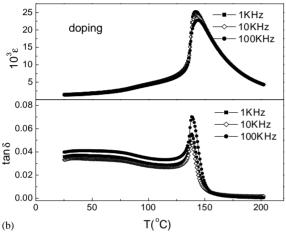


Fig. 3. Temperature dependence of  $\varepsilon$  and  $\tan \delta$  at different frequencies for pure 0.68PMNTa=0.32PT ceramic.

that without Ta addition. This result is consistent with that in 0.65PMNTa-0.35PT and 0.70PMNTa-0.30PT ceramics by Wang [7]. From Figs. 2 and 3, both of the diffusion phase transition (DPT) and frequency dispersion are weak.

In order to examine the relaxor character, the relationship between  $\varepsilon$  and T above  $T_{\rm m}$  (temperature corresponding to the maximum dielectric constant  $\varepsilon_{\rm m}$ ) can be expressed as [8]:

$$\frac{1}{\varepsilon} - \frac{1}{\varepsilon_{\rm m}} = \frac{1}{\varepsilon_{\rm m}} \left( \frac{T - T_{\rm m}}{\delta_4} \right)^{\eta} \tag{2}$$

where,  $\varepsilon_{\rm m}$  corresponds to the maximum value of dielectric constant at  $T_{\rm m}$ ,  $\eta$ , and  $\delta_4$  are constants for all the frequencies.  $\eta$  is called as diffuseness exponent, and can be used to scale the degree of dielectric relaxation in a relaxor FE. When  $\eta=1$ , Eq. (2) is Curie–Weiss law for normal ferroelectrics, and in this situation,  $\delta_4$  is proportional to the Curie constant. When  $\eta=2$ , Eq. (2) represents a typical relaxor ferroelectric, in this case,  $\delta_4$  has the dimension of a temperature and indicates the range of temperature extension for DPT. For many ferroelectrics,  $\eta$  is between 1 and 2 [8]. The relationship between  $\varepsilon$  and T above  $T_{\rm m}$  for 0.68PMNTa–0.32PT ceramics was fitted to Eq. (2). Fig. 4 is the plot of  $\ln(1/\varepsilon-1/\varepsilon_{\rm m})$  versus  $\ln(T-T_{\rm m})$ , which shows a linear relationship, the

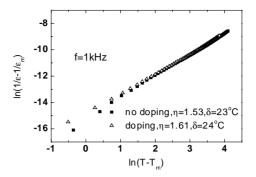


Fig. 4. The relationship between  $\ln(1/\varepsilon-1/\varepsilon_{\rm m})$  and  $\ln(T-T_{\rm m})$  for 0.68PMNTa=0.32PT ceramics.

value of  $\eta$  is 1.53 and 1.61 and the corresponding value of  $\delta_4$  is 23 and 24 °C for 0.68PMN–0.32PT ceramics with 0 and 10 mol.% Ta concentration, respectively. According to our results, the dielectric behavior of 0.68PMNTa–0.32PT has relaxor feature in the range of  $T > T_{\rm m}$ . The value of  $\eta$  with Ta-doping is distinctly larger than that without doping, this means the relaxor feature with Ta-doping is more apparent than without doping.

## 3.3. Piezoelectric properties

The P-E hysteresis loops of 0.68PMNTa-0.32PT ceramics are shown in Fig. 5. The remnant polarization  $P_r$  is 31.1  $\mu$ C/cm<sup>2</sup> and the coercive field  $E_c$  is 4.7 kV/cm for Tadoped 0.68PMN-0.32PT ceramic, while these values are  $26.2 \,\mu\text{C/cm}^2$  and  $4.1 \,\text{kV/cm}$  for pure 0.68 PMN - 0.32 PT ceramic, respectively. The  $P_r$  value is about the same as the spontaneous polarization  $P_s$  defined as the intercept at zero field of the straight-line portion of the hysteresis loop. Both of the  $P_r$  and  $E_c$  decrease with Ta addition. The hysteresis loop is square-like. Fig. 6 shows the electric field-strain behavior of 0.68PMNTa-0.32PT ceramics. The strain curves are typical butterfly shaped. Strong hysteretic strain behavior was observed. For the sample with 0 and 10 mol.% Ta concentration, the remnant strain is  $\sim 0.22$  and 0.34%, while the magnitude of the maximum electrically induced shape change are  $\sim 0.3$  and 0.55% under an electric field of

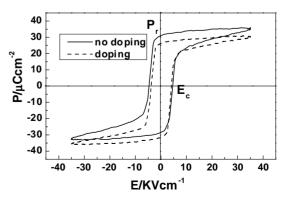


Fig. 5. P-E hysteresis loops of 0.68PMNTa-0.32PT ceramics.

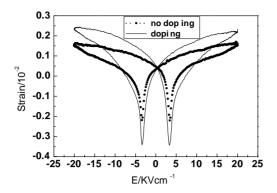


Fig. 6. *E-E* responses for 0.68PMNTa-0.32PT ceramics in a bipolar electric field.

 $\sim$ 20 kV/cm, respectively. Meanwhile, both of the remnant and maximum strain with Ta-doping are found to be distinctly larger than that without doping. The maximum strain with Ta-doping (0.55% under  $E=20\,\mathrm{kV/cm}$ ) is equivalent that of the 0.7PMN–0.3PT single crystal (0.45% under  $E=15\,\mathrm{kV/cm}$ ) [9]. The piezoelectric constant  $d_{33}$  are 458 and 465 pC/N for 0.68PMN–0.32PT ceramics with 0 and 10 mol.% Ta concentration, respectively. It is obvious that the piezoelectric constant with Ta-doping is larger than that without doping, this explains that both of the remnant and maximum strain with Ta-doping is higher than that without doping.

## 4. Summary

In the present study, the perovskite solid solutions 0.68PMNTa–0.32PT were prepared by the one-step calcination method using Mg(NO<sub>3</sub>) instead of MgO as starting chemical. XRD analysis shows that the Ta-doping has little effect on the perovskite formation. The dielectric properties as a function of temperature and P–E and  $\varepsilon$ –E loops were studied for 0.68PMNTa–0.32PT ceramics. The  $T_{\rm m}$  and  $T_{\rm c}$  is shift down for  $\sim$ 13 °C with Ta addition. The  $\varepsilon_{\rm m}$  with Ta-doping ( $\varepsilon_{\rm m}\sim$ 25,000) is higher than that without doping ( $\varepsilon_{\rm m}\sim$ 24,000). Both of the diffusion phase transition and

frequency dispersion are weak. But the relaxor feature with Ta-doping is more apparent than that without doping. Both of the  $P_{\rm r}$  and  $E_{\rm c}$  decrease with Ta addition, and the remnant and maximum strain increase with Ta-doping. With these results we can think 10 mol.% Ta impurity in Nb<sub>2</sub>O<sub>5</sub> is not a threat to perovskite formation but a help to the dielectric and piezoelectric properties of 0.68PMN–0.32PT.

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#### References

- [1] K. Kusumoto, T. Sekiya, Processing and properties of (1 x)Pb-(Mg<sub>1/3</sub>Nb<sub>2/3</sub>)O<sub>3</sub>-xPbTiO<sub>3</sub> solid solutions from PbO- and MgO-excess compositions, Mater. Res. Bull. 33 (9) (1998) 1367–1375.
- [2] S.W. Choi, T.R. Shrout, S.J. Jang, A.S. Bhalla, Morphotropic phase boundary in Pb(Mg<sub>1/3</sub>Nb<sub>2/3</sub>)O<sub>3</sub>–PbTiO<sub>3</sub> system, Mater. Lett. 8 (6/7) (1989) 253–255.
- [3] S.L. Swartz, T.R. Shrout, Fabrication of perovskite lead magnesium niobate, J. Mater. Res. Bull. 17 (10) (1982) 1245–1250.
- [4] P. Ravidranathan, S. Komarneni, A.S. Bhalla, Synthesis and dielectric properties of solution sol–gel-derived 0.9Pb(Mg<sub>1/3</sub>Nb<sub>2/3</sub>) O<sub>3</sub>–0.1PbTiO<sub>3</sub> ceramics, J. Am. Ceram. Soc. 74 (12) (1991) 2996– 2999.
- [5] L.B. Kong, J. Ma, W. Zhu, O.K. Tan, Rapid formation of lead magnesium niobate-based ferroelectric ceramics via a high-energy ball milling process, Mater. Res. Bull. 37 (2002) 459–465.
- [6] K.R. Han, S. Kim, New preparation method of low-temperature sinterable Pb(Mg<sub>1/3</sub>Nb<sub>2/3</sub>)O<sub>3</sub> powder and its dielectric properties, J. Mater. Sci. 35 (2000) 2055–2059.
- [7] J.T. Wang, F. Tang, Effect of Ta-doping on dielectric properties of  $yPbMg_{1/3}(Nb_{(1-x)}Ta_x)_{2/3}O_3-(1-y)PbTiO_3$ , Mater. Chem. Phys. 75 (2002) 86–89.
- [8] L. Mitoseriu, A. Stancu, C. Fedor, P.M. Vilarinho, Analysis of the composition-induced transition from relaxor to ferroelectric state in PbFe<sub>2/3</sub>W<sub>1/3</sub>O<sub>3</sub>-PbTiO<sub>3</sub> solid solutions, J. Appl. Phys. 94 (3) (2003) 1918–1925.
- [9] D. Viehland, J. Powers, Effect of uniaxial stress on the electromechanical properties of 0.7PbMg<sub>1/3</sub>Nb<sub>2/3</sub>O<sub>3</sub>-0.3PbTiO<sub>3</sub> crystals and ceramics, J. Appl. Phys. 89 (3) (2001) 1820–1825.